

Search Notes

Application/Control No.

10/730,151

Examiner

James D. Stein

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385	42-47	5/11/2005	JDS JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	5/11/2005	JDS JP
IEEE INSPEC: waveguide, couple, common region, zone, area, TE and TM polarization	5/11/2005	JDS JP